Noise in Switched-Capacitor Circuits

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What you will learn…

- How to analyze noise in switched-capacitor circuits
- Significance of switch noise vs. OTA noise
  - Power efficient solution
  - Impact of OTA architecture
- Design example for $\Delta\Sigma$ modulator

Review

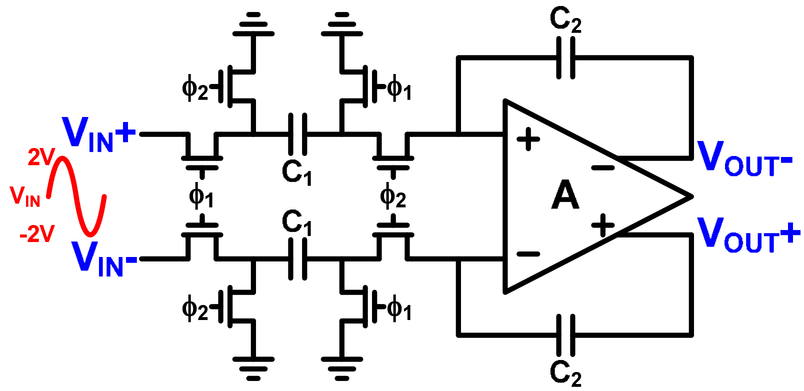
- **Previous analysis of kT/C noise (ignoring OTA/opamp noise)**

  Phase 1: kT/C_1 noise (on each side)

  Phase 2: kT/C_1 added to previous noise (on each side)

  Total Noise (input referred): $2kT/C_1$

  Differentially: $4kT/C_1$



Review

- **SNR (differential)**

  Total noise power: $4kT/C_1$

  Signal power: $(2V)^2/2$

  SNR: $V^2C_1/2kT$

- **SNR (single-ended)**

  Total noise power: $2kT/C_1$ (sampling capacitor C_1)

  Signal power: $V^2/2$ (signal from -V to V)

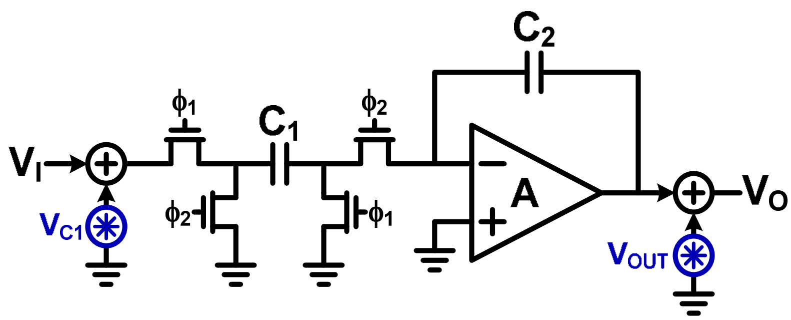
  SNR: $V^2C_1/4kT$

Noise in an Integrator

- **Two noise sources V_{C1} and V_{OUT}**

  V_{C1}: Represents input-referred sampled noise on input switching transistors + OTA

  V_{OUT}: Represents output-referred (non-sampled) noise from OTA

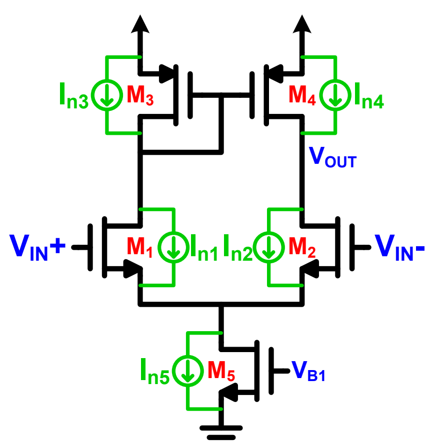


Thermal Noise in OTAs

- **Single-Ended Example**

  Noise current from each transistor is $\overline{I_n^2} = 4kT\gamma g_m$

  Assume $\gamma = 2/3$



Thermal Noise in OTAs

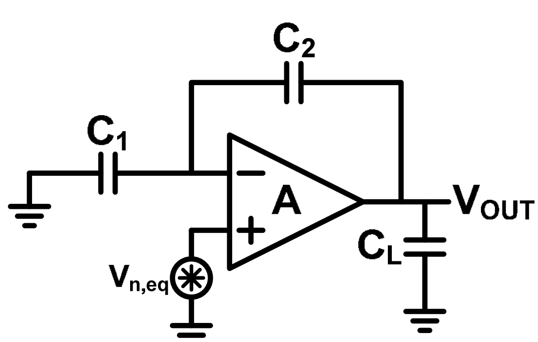
- **Single-Ended Example**
  - Thermal noise in single-ended OTA
  - Assuming paths match, tail current source M_5 does not contribute noise to output
  - PSD of noise voltage in M_1 (and M_2): $\frac{8}{3}\frac{kT}{g_{m1}}$
  - PSD of noise voltage in M_3 (and M_4): $\frac{8}{3}\frac{kTg_{m3}}{g_{m1}^2}$
  - Total input referred noise from M_1 - M_4

$$S_{n,eq} = \frac{16}{3}\frac{kT}{g_{m1}}\left(1+\frac{g_{m3}}{g_{m1}}\right) = \frac{16}{3}\frac{kT}{g_{m1}} n_f$$

  - Noise factor n_f depends on architecture

OTA with capacitive feedback

- **Analyze output noise in single-stage OTA**
  - Use capacitive feedback in the amplification / integration phase of a switched-capacitor circuit



OTA with capacitive feedback

- **Transfer function of closed loop OTA**

$$H(s) = \frac{V_{OUT}}{V_{n,eq}} = \frac{G}{1 + s/\omega_o}$$

where the DC Gain and 1st-pole frequency are

$$G \approx \frac{1}{\beta} = 1 + C_1 / C_2 \qquad \omega_o = \frac{\beta g_{m1}}{C_O}$$

Load capacitance C_O depends on the type of OTA – for a single-stage, it is $C_L+C_1C_2/(C_1+C_2)$, while for a two-stage, it is the compensation capacitor C_C

OTA with capacitive feedback

- **Integrate total noise at output**

$$\overline{V_{OUT}^2} = \int_0^\infty S_{n,eq}(f) \left| H(j2\pi f) \right|^2 df$$

$$= \frac{16}{3} \frac{kT}{g_{m1}} n_f \frac{\omega_o}{4} G^2$$

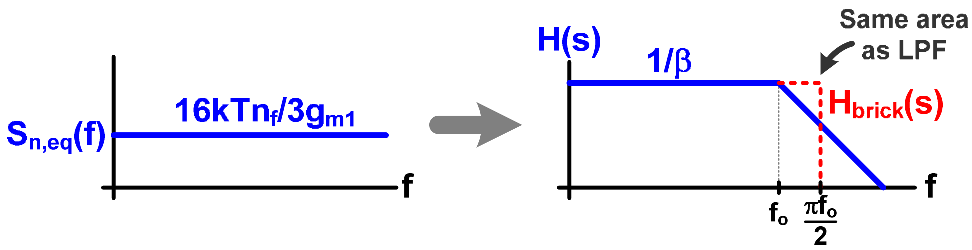
$$= \frac{4kT}{3\beta C_O} n_f$$

Minimum output noise for β=1 is $\frac{4kT}{3C_O} n_f$

Not a function of g_{m1} since bandwidth is proportional to g_{m1} while PSD is inversely proportional to g_{m1}

OTA with capacitive feedback

- Graphically…



Noise is effectively filtered by equivalent brick wall response with cut-off frequency $\pi f_o/2$ (or $\omega_o/4$ or $1/4\tau$)

Total noise at V_{OUT} is the integral of the noise within the brick wall filter (area is simply $\pi f_o/2 \times 1/\beta^2$)

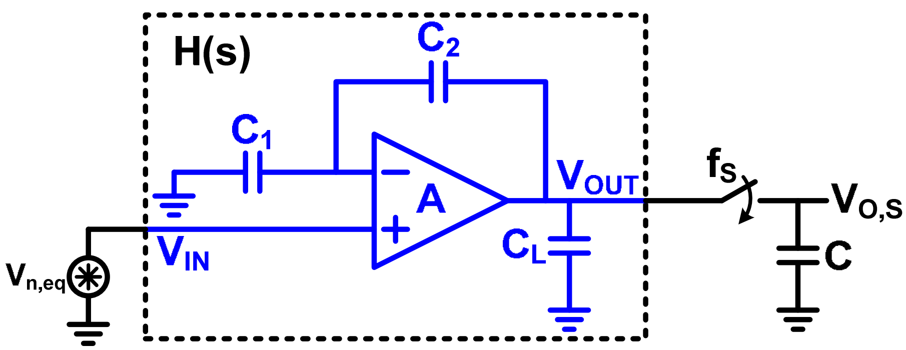
Sampled Thermal Noise

- What happens to noise once it gets sampled?

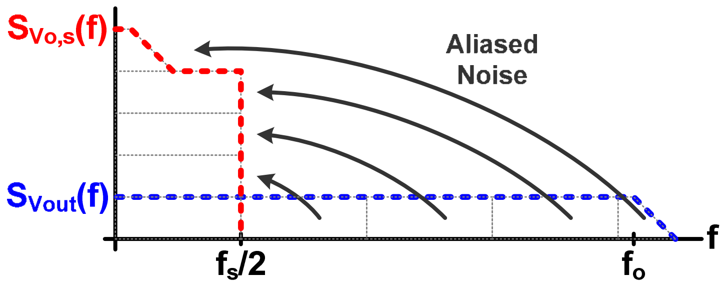
Total noise power is the same

Noise is aliased – folded back from higher frequencies to lower frequencies

PSD of the noise increases significantly



Sampled Thermal Noise



- **Same total area, but PSD is larger from 0 to $f_S/2$**

$$S_{Vout}(f) = \frac{G^2 S_{n,eq}}{4\tau f_S/2} = \frac{\overline{V_{OUT}^2}}{f_S/2} = \frac{4kT}{3\beta C_O} n_f \frac{1}{f_S/2}$$

Low frequency PSD $G^2 S_{n,eq}$ is increased by $\frac{1}{2\tau f_S} = \frac{\pi f_{3dB}}{f_S}$

Sampled Thermal Noise

- **$1/f_{3dB}$ is the settling time of the system, while $1/2f_S$ is the settling period for a two-phase clock**

$$e^{-\frac{1/2f_S}{\tau}} < 2^{-(N+1)}$$

$$\frac{\pi f_{3dB}}{f_S} > (N+1)\ln 2$$

PSD is increased by at least $(N+1)\ln 2$

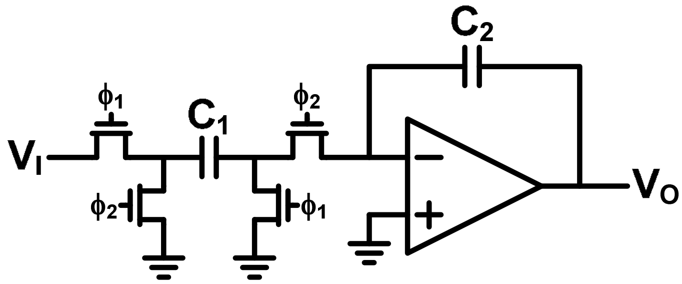
If N = 10 bits, PSD is increased by 7.6, or 8.8dB

- **This is an inherent disadvantage of sampled-data compared to continuous-time systems**

But noise is reduced by oversampling ratio after digital filtering

Noise in a SC Integrator

- Using the parasitic-insensitive SC integrator



- Two phases to consider

  1) Sampling Phase

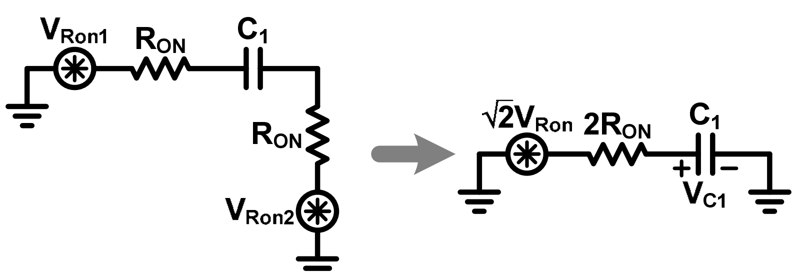
  Includes noise from both ϕ_1 switches

  2) Integrating Phase

  Includes noise from both ϕ_2 switches and OTA

Noise in a SC Integrator

- Phase 1: Sampling



Noise PSD from two switches: $S_{Ron}(f) = 8kTR_{ON}$

Time constant of R-C filter: $\tau = 2R_{ON}C_1$

PSD of noise voltage across C_1

$$S_{C1}(f) = \frac{8kTR_{ON}}{1 + (2\pi f \tau)^2}$$

Noise in a SC Integrator

- **Phase 1: Sampling**

  Integrated across entire spectrum, total noise power in C_1 is

$$\overline{V^2_{C1,sw1}} = \frac{8kTR_{ON}}{4\tau} = \frac{kT}{C_1}$$

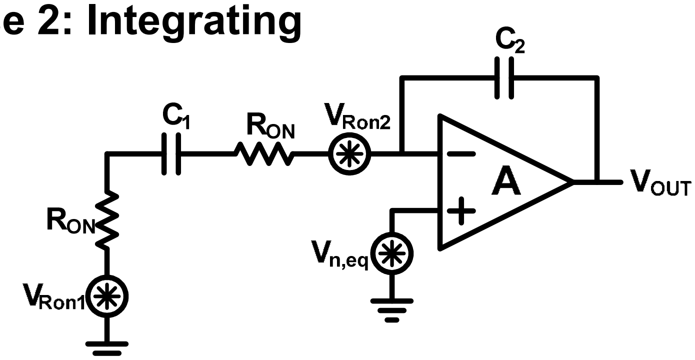
  Independent of R_{ON} (PSD is proportional to R_{ON}, bandwidth is inversely proportional to R_{ON})

  After sampling, charge is trapped in C_1

ANALOG DEVICES

Noise in a SC Integrator

- **Phase 2: Integrating**



- **Two noise sources: switches and OTA**

  Noise PSD from two switches: $S_{Ron}(f) = 8kTR_{ON}$

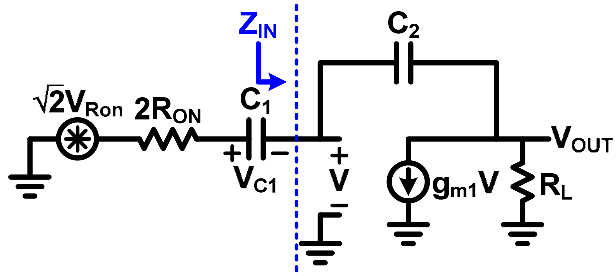
  Noise PSD from OTA: $S_{vn,eq}(f) = \frac{16}{3}\frac{kT}{g_{m1}}n_f$

  Noise power across C_1 charges to $2\overline{V^2_{Ron}} + \overline{V^2_{n,eq}}$

ANALOG DEVICES

Noise in a SC Integrator

- What is the time-constant?



Analysis shows that $Z_{IN} = \dfrac{1/sC_2 + R_L}{1 + g_{m1}R_L}$

For large R_L, assume that $Z_{IN} \approx \dfrac{1}{g_{m1}}$

Resulting time constant $\tau = (2R_{ON} + 1/g_{m1})C_1$

ANALOG DEVICES

Noise in a SC Integrator

- Total noise power with both switches and OTA on integrating phase

$$\overline{V_{C1,op}^2} = \frac{S_{vn,eq}(f)}{4\tau} = \frac{16kT}{3g_{m1}}\frac{n_f}{4(2R_{ON} + 1/g_{m1})C_1} = \frac{4kT}{3C_1}\frac{n_f}{(1+x)}$$

$$\overline{V_{C1,sw2}^2} = \frac{S_{Ron}(f)}{4\tau} = \frac{8kTR_{ON}}{4(2R_{ON} + 1/g_{m1})C_1} = \frac{kT}{C_1}\frac{x}{(1+x)}$$

Introduced extra parameter $x = 2R_{ON}g_{m1}$

ANALOG DEVICES

Noise in a SC Integrator

- **Total noise power on C1 from both phases**

$$\overline{V_{C1}^2} = \overline{V_{C1,op}^2} + \overline{V_{C1,sw1}^2} + \overline{V_{C1,sw2}^2}$$
$$= \frac{4kT}{3C_1}\frac{n_f}{(1+x)} + \frac{kT}{C_1}\frac{x}{(1+x)} + \frac{kT}{C_1}$$
$$= \frac{kT}{C_1}\left(\frac{4n_f/3+1+2x}{1+x}\right)$$

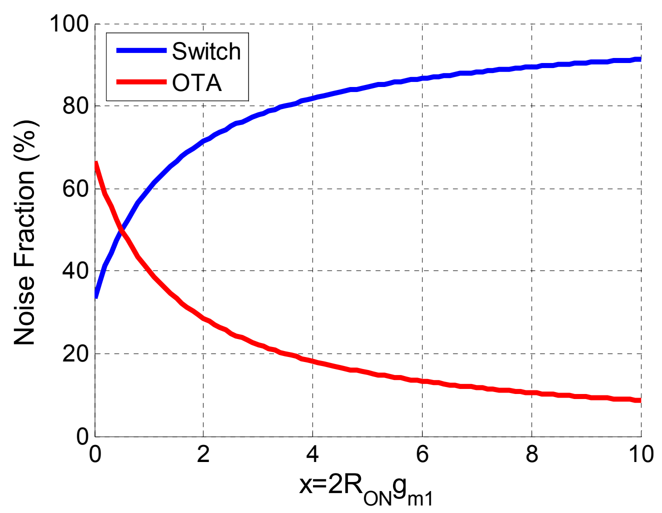
Lowest possible noise achieved if $x \to \infty$

In this case, $\overline{V_{C1}^2} = \dfrac{2kT}{C_1}$

What was assumed to be the total noise was actually the least possible noise!

Noise Contributions

- **Percentage noise contribution from switches and OTA (assume n_f=1.5)**



Noise Contributions

- **When $g_{m1} >> 1/R_{ON}$ ($x >> 1$)…**
  - Switch dominates both bandwidth and noise
  - Total noise power is minimized

- **When $g_{m1} << 1/R_{ON}$ ($x << 1$)…**
  - OTA dominates both bandwidth and noise
  - Power-efficient solution
    - Minimize g_{m1} (and power) for a given settling time and noise

$$g_{m1} = \frac{kT}{\tau \overline{V_{C1}^2}} \left(\frac{4}{3} n_f + 1 + 2x \right)$$

Minimized for x=0

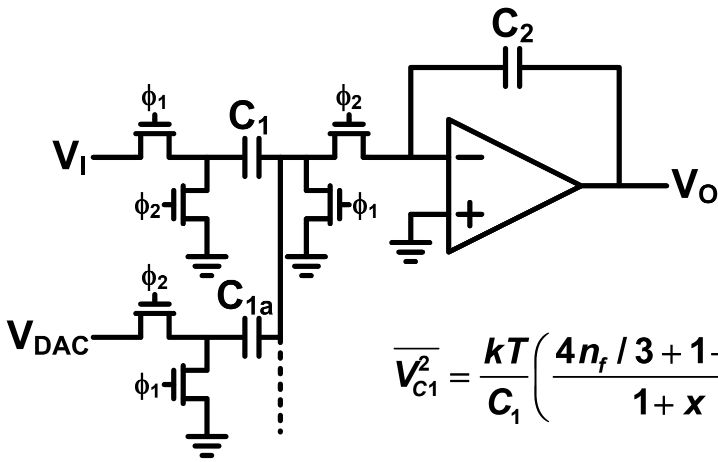
Maximum Noise

- **How much larger can the noise get?**
  - Depends on n_f… (table excludes cascode noise)

Architecture	Relative V_{EFF}'s	n_f	Maximum Noise (x=0)	+dB
Telescopic/ Diff.Pair	$V_{EFF,1}=V_{EFF,n}/2$	1.5	$3 \cdot kT/C_1$	1.76
Telescopic/ Diff.Pair	$V_{EFF,1}=V_{EFF,n}$	2	$3.67 \cdot kT/C_1$	2.63
Folded Cascode	$V_{EFF,1}=V_{EFF,n}/2$	2.5	$4.33 \cdot kT/C_1$	3.36
Folded Cascode	$V_{EFF,1}=V_{EFF,n}$	4	$6.33 \cdot kT/C_1$	5.01

Separate Input Capacitors

- **Using separate input caps increases noise**
  - **Each additional input capacitor adds to the total noise**
  - **Separate caps help reduce signal dependent disturbances in the DAC reference voltages**



$$\overline{V_{C1}^2} = \frac{kT}{C_1}\left(\frac{4n_f/3+1+2x}{1+x}\right)\left(1+\frac{C_{1a}}{C_1}+\dots\right)$$

Differential vs. Single-Ended

- **All previous calculations assumed single-ended operation**
  - **For same settling time, $g_{m1,2}$ is the same, resulting in the same total power [0dB]**
  - **Differential input signal is twice as large [gain 6dB]**
  - **Differential operation has twice as many caps and therefore twice as much capacitor noise (assume same size per side – C_1 and C_2) [lose ~1.2dB for n_f=1.5, x=0… less for larger n_f]**

- **Net Improvement: ~4.8dB**

Differential vs. Single-Ended

- **Single-Ended Noise**

$$\overline{V_{C1,se}^2} = \frac{kT}{C_1}\left(\frac{4n_f/3+1+2x}{1+x}\right)$$

- **Differential Noise**

$$\overline{V_{C1,diff}^2} = \overline{V_{C1,op}^2} + \overline{V_{C1,sw1}^2} + \overline{V_{C1,sw2}^2}$$

$$= \frac{4kT}{3C_1}\frac{n_f}{(1+x)} + \frac{2kT}{C_1}\frac{x}{(1+x)} + \frac{2kT}{C_1}$$

$$= \frac{kT}{C_1}\left(\frac{4n_f/3+2+4x}{1+x}\right)$$

- **Relative Noise (for n_f=1.5, x=0)**

$$\frac{\overline{V_{C1,diff}^2}}{\overline{V_{C1,se}^2}} = \frac{4n_f/3+2+4x}{4n_f/3+1+2x} = \frac{4}{3}$$

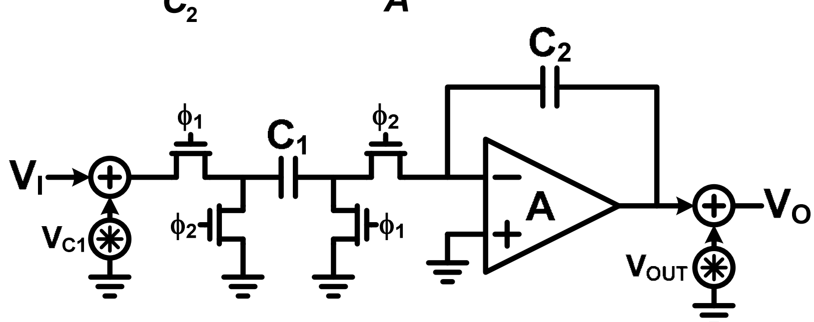
Noise in an Integrator

- **What is the total output-referred noise in an integrator?**

Assume an integrator transfer function

$$H(z) = \frac{kz^{-1}}{1+\mu(1+k)-(1+\mu)z^{-1}} \approx \frac{kz^{-1}}{1-z^{-1}}$$

where $k = \frac{C_1}{C_2}$ **and** $\mu = \frac{1}{A}$



Noise in an Integrator

- **Total output-referred noise PSD**

$$S_{INT}(f) = S_{C1}(f)\left|H(z)\right|^2 + S_{OUT}(f)$$

where $\overline{V_{OUT}^2} = \dfrac{4kT}{3\beta C_O} n_f$

and $\overline{V_{C1}^2} = \dfrac{kT}{C_1}\left(\dfrac{4n_f/3+1+2x}{1+x}\right)$

Since all noise sources are sampled, white PSDs

$$S_x = \frac{\overline{V_x^2}}{f_S/2}$$

To find output-referred noise for a given OSR in a $\Delta\Sigma$ modulator:

$$\overline{V_{INT}^2} = \int_0^{f_S/(2\cdot OSR)} S_{INT}(f)\,df$$

ANALOG DEVICES

Noise in a $\Delta\Sigma$ Modulator

- **How do we find the total input-referred noise in a $\Delta\Sigma$ modulator?**
  1) Find all thermal noise sources
  2) Find PSDs of the thermal noise sources
  3) Find transfer functions from each noise source to the output
  4) Using the transfer functions, integrate all PSDs from DC to the signal band edge $f_S/2\cdot OSR$
  5) Sum the noise powers to determine the total output thermal noise
  6) Input noise = output noise (assuming STF is ~1 in the signal band)

ANALOG DEVICES

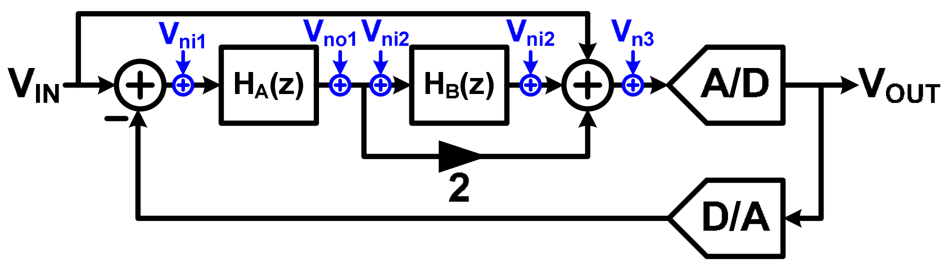
Noise in a ΔΣ Modulator

- **Example**

  f_S = 100MHz, T = 10ns, OSR = 32
  SNR = 80dB (13-bit resolution)
  Input Signal Power = 0.25V^2 (-6dB from 1V^2)
  Noise Budget: 75% thermal noise
  Total input referred thermal noise:

Noise in a ΔΣ Modulator

1) **Find all thermal noise sources**



$$\overline{V_{ni1}^2} = \frac{kT}{C_{1A}}\left(\frac{4n_{fA}/3+1+2x_A}{1+x_A}\right) \qquad \overline{V_{ni2}^2} = \frac{kT}{C_{1B}}\left(\frac{4n_{fB}/3+1+2x_B}{1+x_B}\right)$$

$$\overline{V_{no1}^2} = \frac{4kT}{3\beta_A C_{OA}}n_{fA} \qquad \overline{V_{no2}^2} = \frac{4kT}{3\beta_B C_{OB}}n_{fB}$$

$$\overline{V_{n3}^2} = \frac{2kT}{C_{f1}}\left(1+\frac{C_{f2}}{C_{f1}}+\frac{C_{f3}}{C_{f1}}\right) = \frac{2kT}{C_{f1}}(1+2+1)$$

Noise in a ΔΣ Modulator

2) **Find PSDs of the thermal noise sources**

For each of the mean square voltage sources,

$$S_x = \frac{\overline{V_x^2}}{f_S/2}$$

3) **Find transfer functions from each noise source to the output**

Assume ideal integrators

$$H_A(z) = H_B(z) = \frac{z^{-1}}{1 - z^{-1}}$$

$$STF(z) = 1$$

$$NTF(z) = (1 - z^{-1})^2 = \frac{1}{1 + 2H(z) + H(z)^2}$$

Noise in a ΔΣ Modulator

3) **Find transfer functions from each noise source to the output**

From input of $H_A(z)$ to output…

$$NTF_{i1}(z) = \left(2H(z) + H(z)^2\right) NTF(z)$$

$$= \frac{2H(z) + H(z)^2}{1 + 2H(z) + H(z)^2} = 2z^{-1} - z^{-2}$$

From output of $H_A(z)$ to output…

$$NTF_{o1}(z) = \left(2 + H(z)\right) NTF(z)$$

$$= \frac{2 + H(z)}{1 + 2H(z) + H(z)^2} = (1 - z^{-1})(2 - z^{-1})$$

Noise in a ΔΣ Modulator

3) Find transfer functions from each noise source to the output

From input of $H_B(z)$ to output…

$$NTF_{i2}(z) = H(z)NTF(z)$$

$$= \frac{H(z)}{1 + 2H(z) + H(z)^2} = z^{-1}(1 - z^{-1})$$

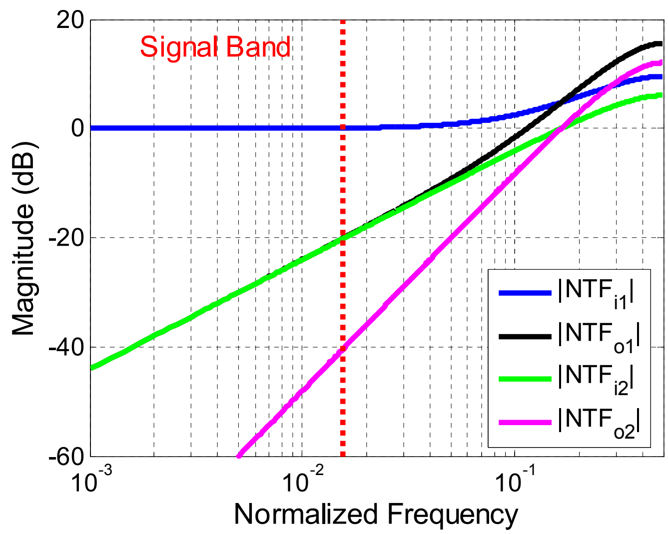
From output of $H_B(z)$ to output (equal to transfer function at input of summer to output)…

$$NTF_{o2}(z) = NTF(z) = (1 - z^{-1})^2$$

Noise in a ΔΣ Modulator

3) Find transfer functions from each noise source to the output

Most significant is NTF_{i1}



Noise in a ΔΣ Modulator

4) Using the transfer functions, integrate all PSDs from DC to the signal band edge $f_S/2 \cdot OSR$

Use MATLAB/Maple to solve the integrals…

$$\overline{N_{i1}^2} = \frac{\overline{V_{ni1}^2}}{f_S/2} \int_0^{f_S/(2 \cdot OSR)} \left| NTF_{i1}(f) \right|^2 df$$

$$= \frac{\overline{V_{ni1}^2}}{f_S/2} \left[\frac{5f_S}{2 \cdot OSR} - \frac{2f_S}{\pi} \sin\left(\frac{\pi}{OSR} \right) \right]$$

$$\overline{N_{o1}^2} = \frac{\overline{V_{no1}^2}}{f_S/2} \int_0^{f_S/(2 \cdot OSR)} \left| NTF_{o1}(f) \right|^2 df$$

$$= \frac{\overline{V_{no1}^2}}{f_S/2} \left[\frac{7f_S}{OSR} + \frac{2f_S}{\pi} \sin\left(\frac{\pi}{OSR} \right) \cos\left(\frac{\pi}{OSR} \right) - \frac{9f_S}{\pi} \sin\left(\frac{\pi}{OSR} \right) \right]$$

Noise in a ΔΣ Modulator

4) Using the transfer functions, integrate all PSDs from DC to the signal band edge $f_S/2 \cdot OSR$

$$\overline{N_{i2}^2} = \frac{\overline{V_{ni2}^2}}{f_S/2} \left[\frac{f_S}{OSR} - \frac{f_S}{\pi} \sin\left(\frac{\pi}{OSR} \right) \right]$$

$$\overline{N_{o2}^2} = \frac{\overline{V_{no2}^2} + \overline{V_{n3}^2}}{f_S/2} \left[\frac{3f_S}{OSR} + \frac{f_S}{\pi} \sin\left(\frac{\pi}{OSR} \right) \cos\left(\frac{\pi}{OSR} \right) - \frac{4f_S}{\pi} \sin\left(\frac{\pi}{OSR} \right) \right]$$

(Some simplifications can be made for large OSR)

Noise in a ΔΣ Modulator

5) **Sum the noise powers to determine the total output thermal noise**

Assume $x_A = x_B = 0.1$ and $n_{fA} = n_{fB} = 1.5$

$$\overline{V_{TH}^2} \approx \frac{2.9kT}{C_{1A}}\frac{1}{OSR} + \frac{2kT}{\beta_A C_{OA}}\frac{\pi^2}{3OSR^3} + \frac{2.9kT}{C_{1B}}\frac{\pi^2}{3OSR^3} + \frac{2kT}{\beta_B C_{OB}}\frac{\pi^4}{5OSR^5} + \frac{8kT}{C_{f1}}\frac{\pi^4}{5OSR^5}$$

With an OSR of 32, first term is most significant (assume $\beta_A = \beta_B = 1/3$)

$$\overline{V_{TH}^2} \approx 9.1\times10^{-2}\frac{kT}{C_{1A}} + 6.0\times10^{-4}\frac{kT}{C_{OA}} + 2.9\times10^{-4}\frac{kT}{C_{1B}} + \ldots$$

Noise in a ΔΣ Modulator

6) **Input noise = output noise (assuming STF is ~1 in the signal band)**

$$\overline{V_{TH}^2} \approx 9.1\times10^{-2}\frac{kT}{C_{1A}} = (43.4\mu V)^2$$

=> C1A = 200fF

Assuming other capacitors are smaller than C_{1A}, then subsequent terms are insignificant and the approximation is valid

If lower oversampling ratios are used, other terms may become more significant in the calculation

Noise in a Pipeline ADC

- Similar procedure to ΔΣ modulator, except transfer functions are much easier to compute

- Differences…
  - Input refer all noise sources
  - Gain from each stage to the input is a scalar
  - Noise from later stages will be more significant since typical stage gains are as low as 2
  - Sample-and-Hold adds extra noise which is input referred with a gain of 1
  - Entire noise power is added since the signal band is from 0 to $f_S/2$ (OSR=1)

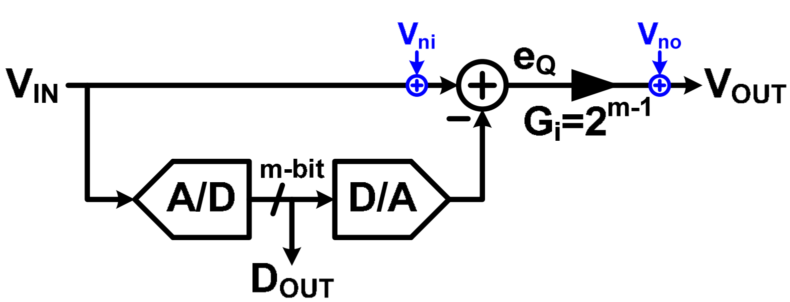
ANALOG DEVICES

Noise in a Pipeline ADC

- Example
  - If each stage has a gain G_1, G_2, … G_N

$$\overline{N_i^2} = \overline{V_{ni1}^2} + \frac{\overline{V_{no1}^2} + \overline{V_{ni2}^2}}{G_1^2} + \frac{\overline{V_{no2}^2} + \overline{V_{ni3}^2}}{G_1^2 G_2^2} + \cdots + \frac{\overline{V_{noN}^2}}{G_1^2 G_2^2 \cdots G_N^2}$$

  - S/H stage noise will add directly to V_{ni1}



ANALOG DEVICES

Further Reading

- Appendix C of *Understanding Delta-Sigma Data Converters*, Schreier and Temes
- Schreier et al., *Design-Oriented Estimation of Thermal Noise in Switched-Capacitor Circuits*, TCAS-I, Nov. 2005